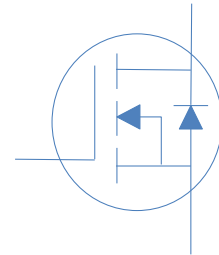


45V N-Ch Power MOSFET

V_{DS}		45	V
$R_{DS(on),typ}$	$V_{GS}=10V$	3.5	$m\Omega$
$R_{DS(on),typ}$	$V_{GS}=4.5V$	4.6	$m\Omega$
I_D (Silicon Limited)		114	A

- ◇
- ◇
- ◇
- ◇
- ◇

- ◇
- ◇
- ◇
- ◇
- ◇



Part Number	Package	Marking
HGP045NE4SL	TO-220	GP045NE4SL

Absolute Maximum Ratings at $T_J=25$ (unless otherwise specified)

Parameter	Symbol	Conditions	Value	Unit
Continuous Drain Current (Silicon Limited)	I_D	$T_C=25$	114	A
		$T_C=100$	80	
Drain to Source Voltage	V_{DS}	-	45	V
Gate to Source Voltage	V_{GS}	-	± 20	V
Pulsed Drain Current	I_{DM}	-	350	A
Avalanche Energy, Single Pulse	E_{AS}	$L=0.3mH, T_C=25$	60	mJ
Power Dissipation	P_D	$T_C=25$	125	W
Operating and Storage Temperature	T_J, T_{stg}	-	-55 to 175	

Absolute Maximum Ratings

Parameter	Symbol	Max	Unit
Thermal Resistance Junction-Case	$R_{\theta JC}$	1.2	$^{\circ}W$
Thermal Resistance Junction-Ambient	$R_{\theta JA}$	50	$^{\circ}W$

Electrical Characteristics at $T_j=25$ (unless otherwise specified)

Static Characteristics

Parameter	Symbol	Conditions	Value			Unit
			min	typ	max	
Drain to Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS}=0V, I_D=250\mu A$	45	-	-	V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS}=V_{DS}, I_D=250\mu A$	1	1.8	2.2	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{GS}=0V, V_{DS}=45V, T_j=25$	-	-	1	μA
		$V_{GS}=0V, V_{DS}=45V, T_j=100$	-	-	100	μA
Gate to Source Leakage Current	I_{GSS}	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	± 100	nA
Drain to Source on Resistance	$R_{DS(on)}$	$V_{GS}=10V, I_D=20A$	-	-	-	m Ω
		$V_{GS}=4.5V, I_D=20A$	-	-	7.0	m Ω
Gate Resistance	R_G	$V_{DS}=5V, I_D=20A$	-	40	-	S
		$V_{GS}=0V, V_{DS}$ Open, $f=1MHz$	-	-	-	Ω
Output Capacitance	C_{oss}			2159	-	
				118	-	
Diode Forward Voltage	V_{SD}					V
Reverse Recovery Time	t_{rr}	$V_R=20V, I_F=20A, dI_F/dt=200A/\mu s$	-	30	-	ns
Reverse Recovery Charge	Q_{rr}					

Fig 1. Typical Output Characteristics

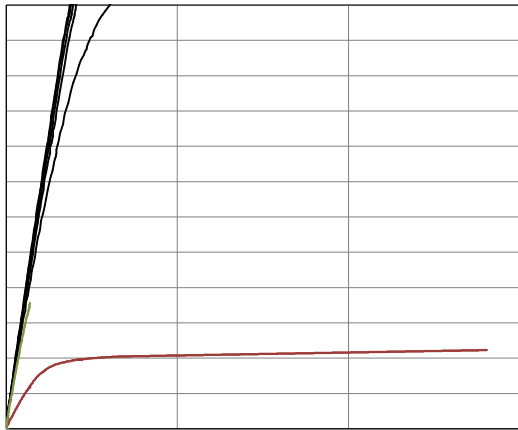


Figure 2. On-Resistance vs. Gate-Source Voltage

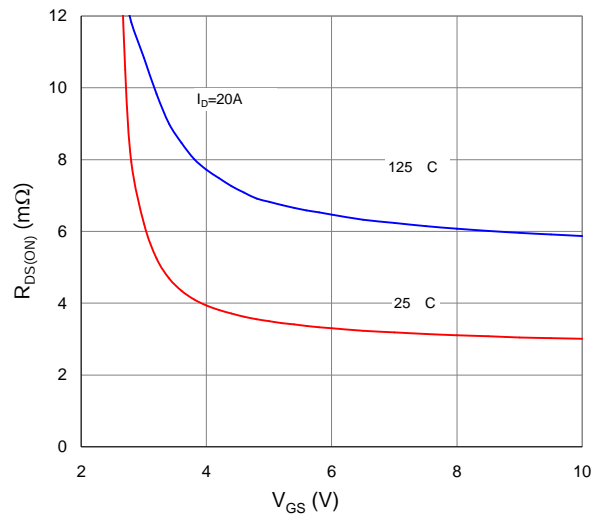


Figure 3. On-Resistance vs. Drain Current and Gate Voltage

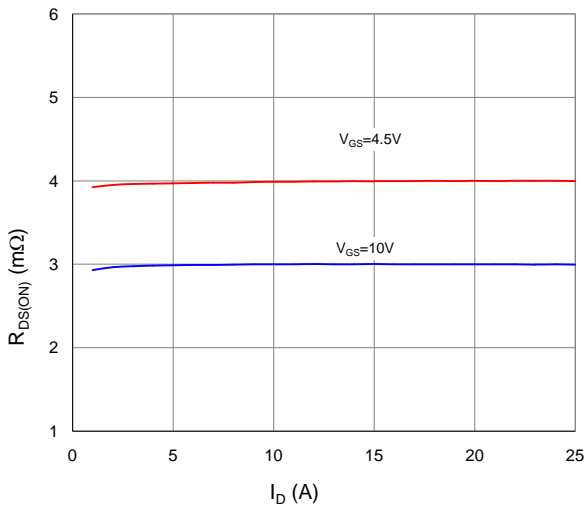


Figure 4. Normalized On-Resistance vs. Junction Temperature

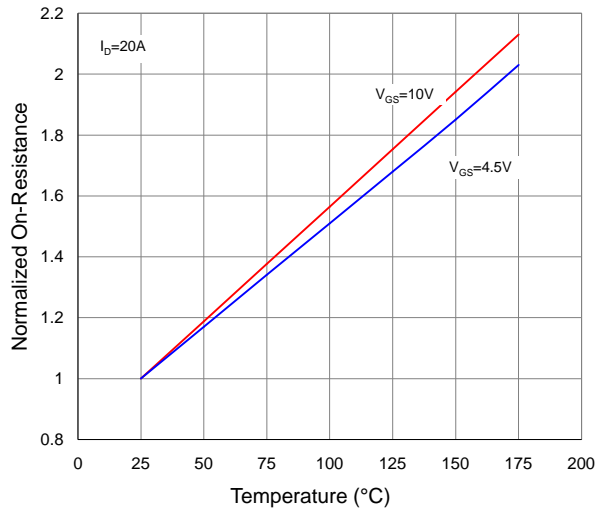


Figure 5. Typical Transfer Characteristics

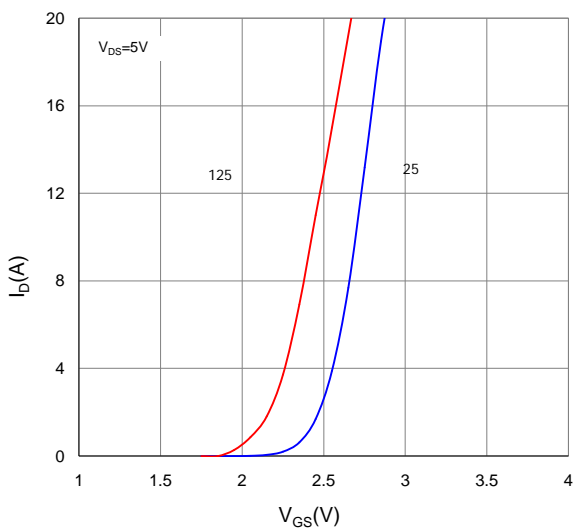


Figure 6. Typical Source-Drain Diode Forward Voltage

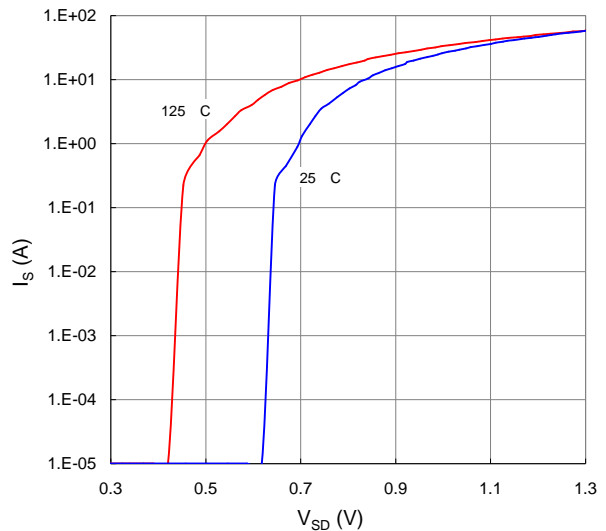


Figure 7. Typical Gate-Charge vs. Gate-to-Source Voltage

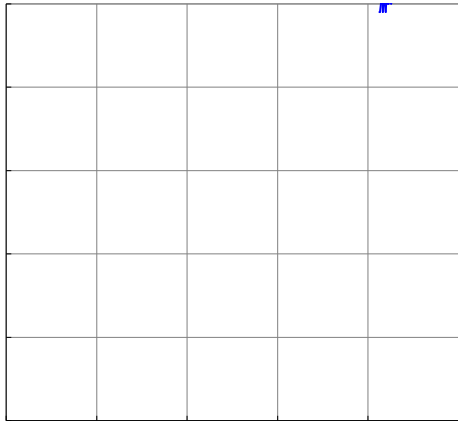


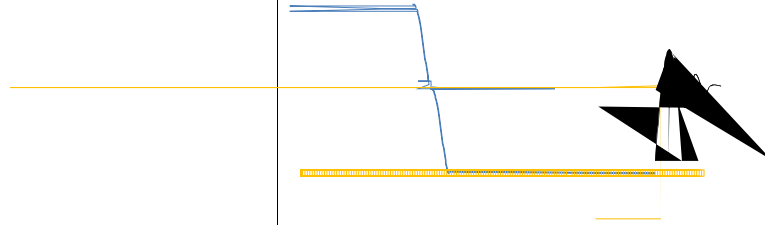
Figure 8. Typical Capacitance vs. Drain-to-Source Voltage

Figure 9. Maximum Safe Operating Area

Figure 10. Maximun Drain Current vs. Case Temperature

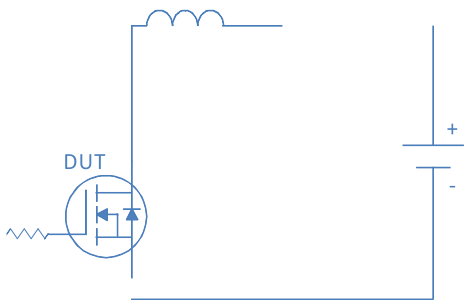
Figure 11. Normalized Maximum Transient Thermal Impedance, Junction-to-Case

Inductive switching Test



Gate Charge Test

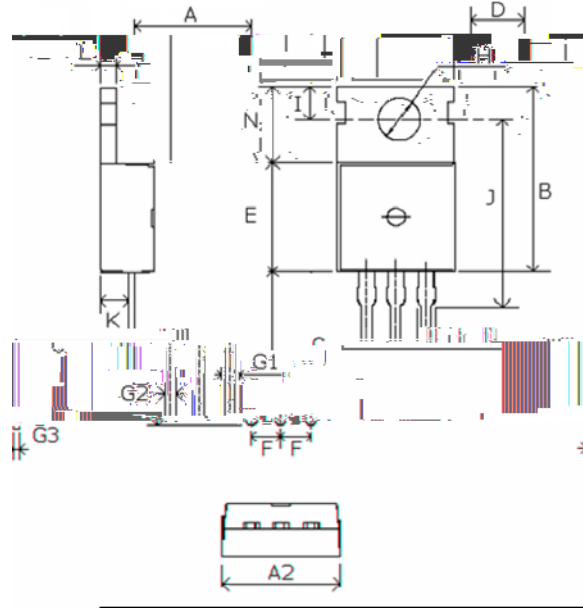
Uclamped Inductive Switching (UIS) Test



Diode Recovery Test

Package Outline

TO-220, 3 leads



Dimensions in mm unless otherwise specified

Symbol	Min	Nom	Max
A	9.66	9.97	10.28
A2	9.80	10.00	10.20
B	15.60	15.70	15.80
C	12.70	13.48	14.27
D	4.30	4.50	4.70
E	9.00	9.20	9.40
F		2.54	
G1	1.32	1.52	1.72
G2	0.70	0.82	0.95
G3	0.45	0.52	0.60
H	3.50	3.60	3.70
I	2.70	2.80	2.90
J	15.70	15.97	16.25
K	2.20	2.40	2.60
L	1.15	1.27	1.40
N	6.40	6.60	6.80